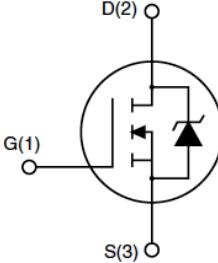


## Description

<p><b>Features</b></p> <ul style="list-style-type: none"> <li>● 650V,20A</li> <li>● <math>R_{DS(ON)} = 0.35\Omega</math> (Typ.) @ <math>V_{GS} = 10V</math>, <math>I_D = 10A</math></li> <li>● Fast Switching</li> <li>● Improved dv/dt Capability</li> <li>● 100% Avalanche Tested</li> </ul>	<p><b>Application</b></p> <ul style="list-style-type: none"> <li>● Switch Mode Power Supply(SMPS)</li> <li>● Uninterruptible Power Supply(UPS)</li> <li>● Power Factor Correction (PFC)</li> </ul>
 TO-220F  TO-247  TO-3P  Schematic Diagram	

## Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise specified)

Symbol	Parameter	Max.		Units
		TO-220F	TO-247/TO-3P	
$V_{DSS}$	Drain-Source Voltage	650		V
$V_{GSS}$	Gate-Source Voltage	$\pm 30$		V
$I_D$	Continuous Drain Current	$T_c = 25^\circ C$	20	A
		$T_c = 100^\circ C$	13	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>	80		A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>	1350		mJ
$P_D$	Power Dissipation	$T_c = 25^\circ C$	167	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.75	0.3	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	60	60	$^\circ C/W$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150		$^\circ C$

## Electrical Characteristics ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	650	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = 650\text{V}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	-	-	1	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 30\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D=250\mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static Drain-Source on-Resistance note3	$V_{GS} = 10\text{V}, I_D = 10\text{A}$	-	0.35	0.45	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	-	2978	-	pF
$C_{oss}$	Output Capacitance		-	291	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	40	-	pF
$Q_g$	Total Gate Charge	$V_{DD} = 520\text{V}, I_D = 20\text{A}, V_{GS} = 10\text{V}$	-	80	-	nC
$Q_{gs}$	Gate-Source Charge		-	12	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	34	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 325\text{V}, I_D = 20\text{A}, R_G = 25\Omega$	-	37	-	ns
$t_r$	Turn-on Rise Time		-	66	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	175	-	ns
$t_f$	Turn-off Fall Time		-	84	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	20	A	
$I_{sM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	80	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 20\text{A}$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_s = 20\text{A}, dI/dt = 100\text{A}/\mu\text{s}$	-	450	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	7.1	-	$\mu\text{C}$

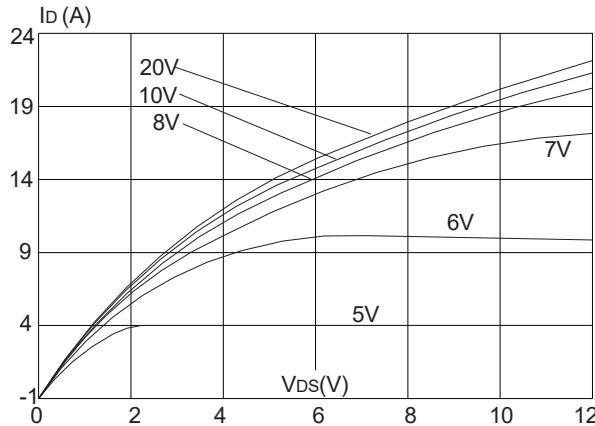
Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2.  $I_{AS} = 16\text{A}, V_{DD} = 50\text{V}, R_G = 25 \Omega, \text{Starting } T_J = 25^\circ\text{C}$

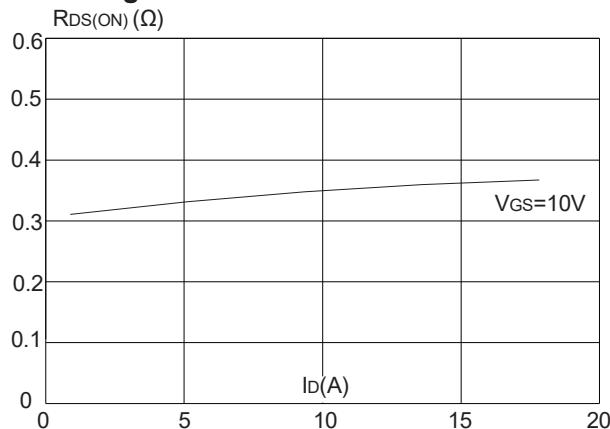
3. Pulse Test: Pulse Width  $\leq 350\mu\text{s}$ , Duty Cycle  $\leq 1\%$

## Typical Performance Characteristics

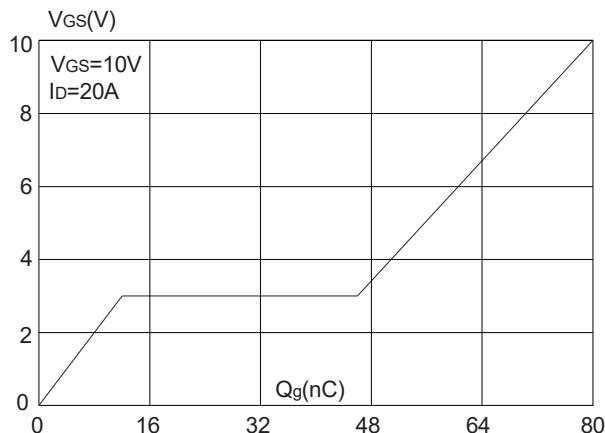
**Figure1:** Output Characteristics



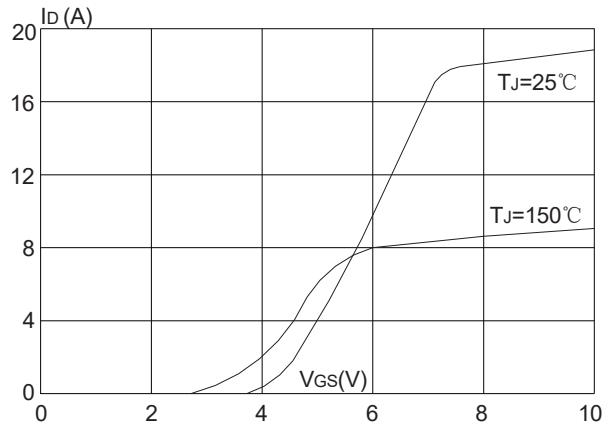
**Figure 3:** On-resistance vs. Drain Current



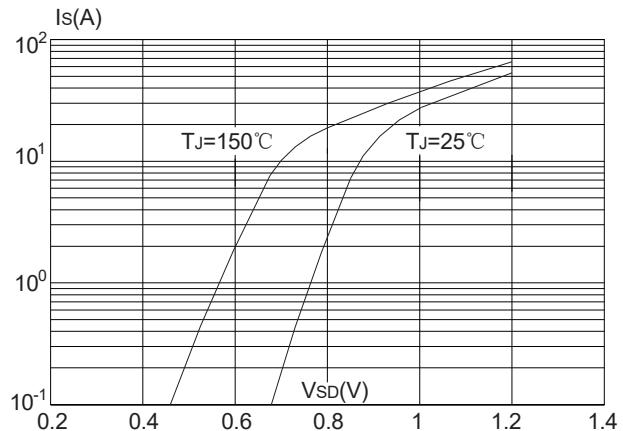
**Figure 5: Gate Charge Characteristics**



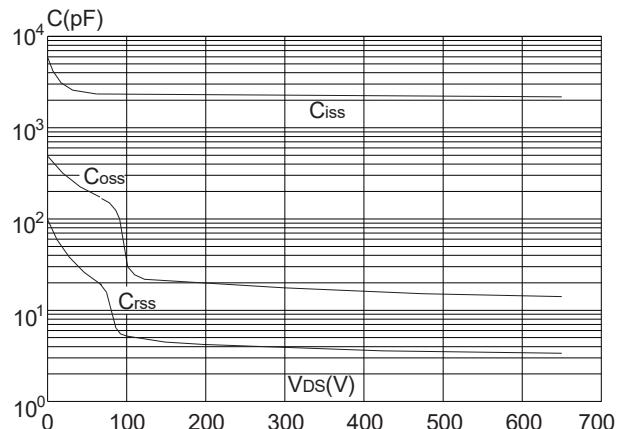
**Figure 2:** Typical Transfer Characteristics



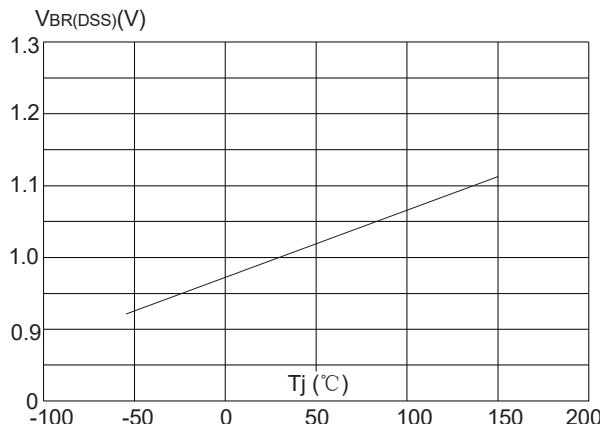
**Figure 4:** Body Diode Characteristics



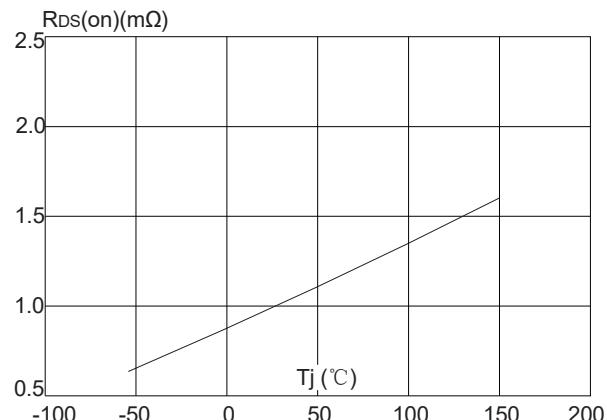
**Figure 6:** Capacitance Characteristics



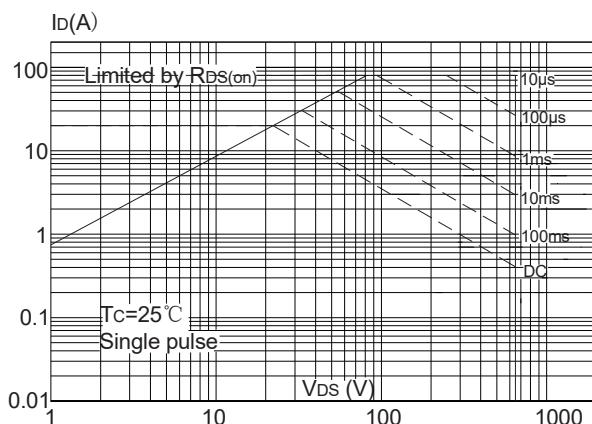
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



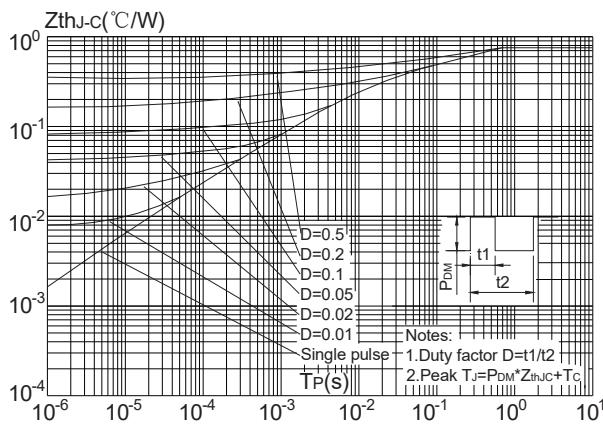
**Figure 8:** Normalized on Resistance vs. Junction Temperature



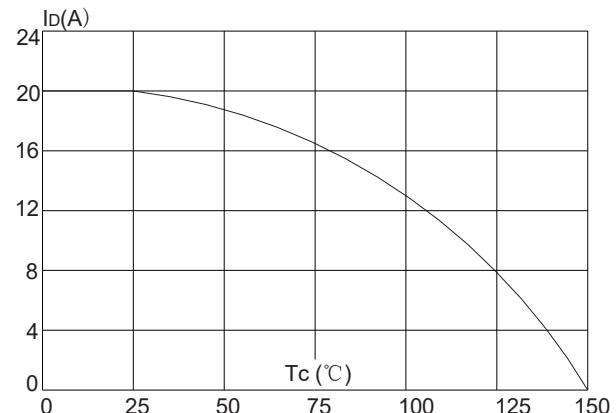
**Figure 9:** Maximum Safe Operating Area



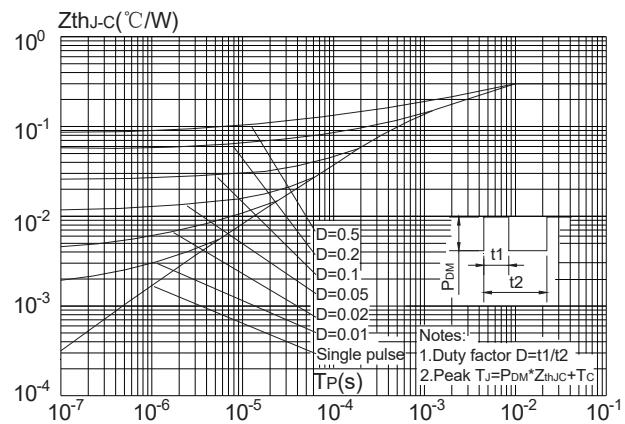
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-220F)



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure.12:** Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-247, TO-3P)



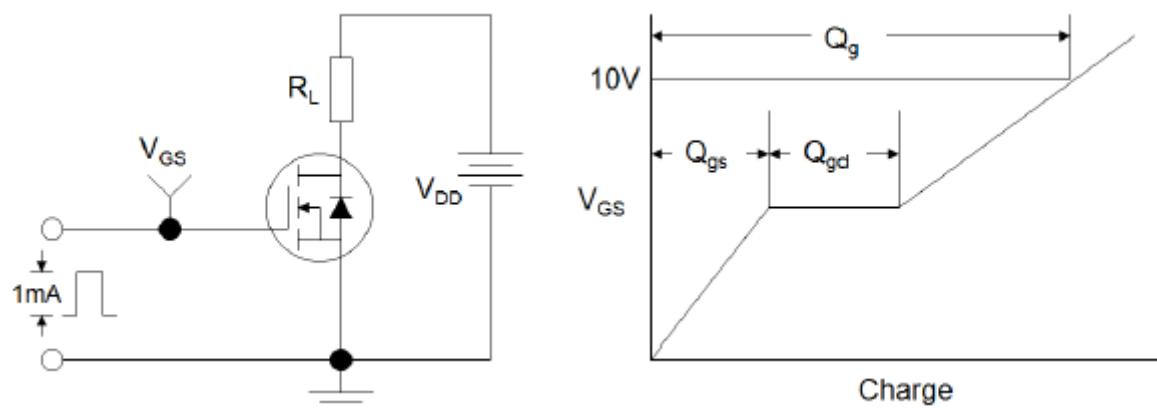


Figure1:Gate Charge Test Circuit & Waveform

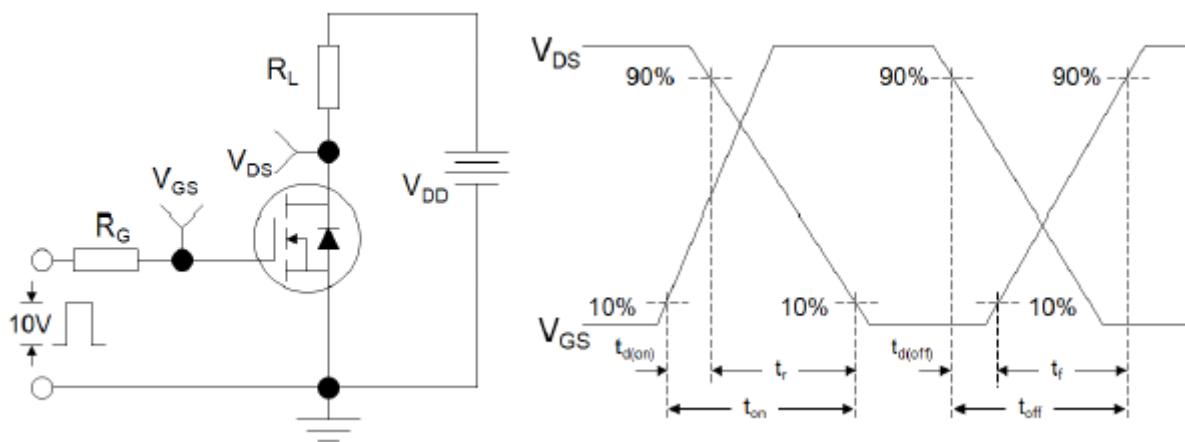


Figure 2: Resistive Switching Test Circuit & Waveforms

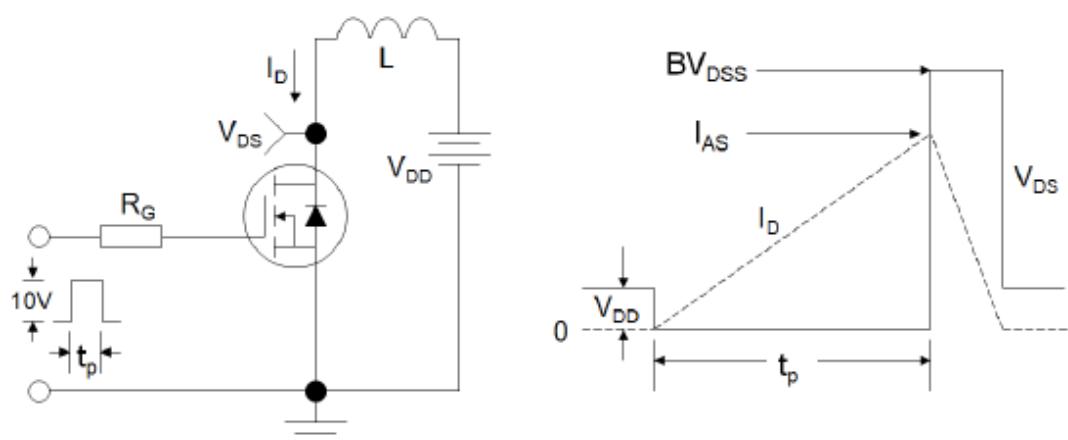
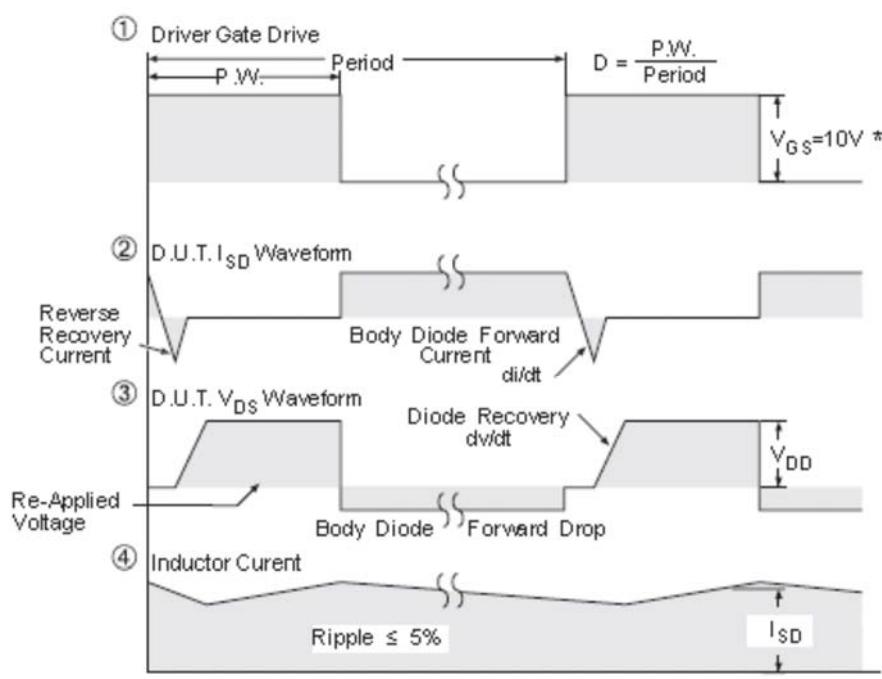
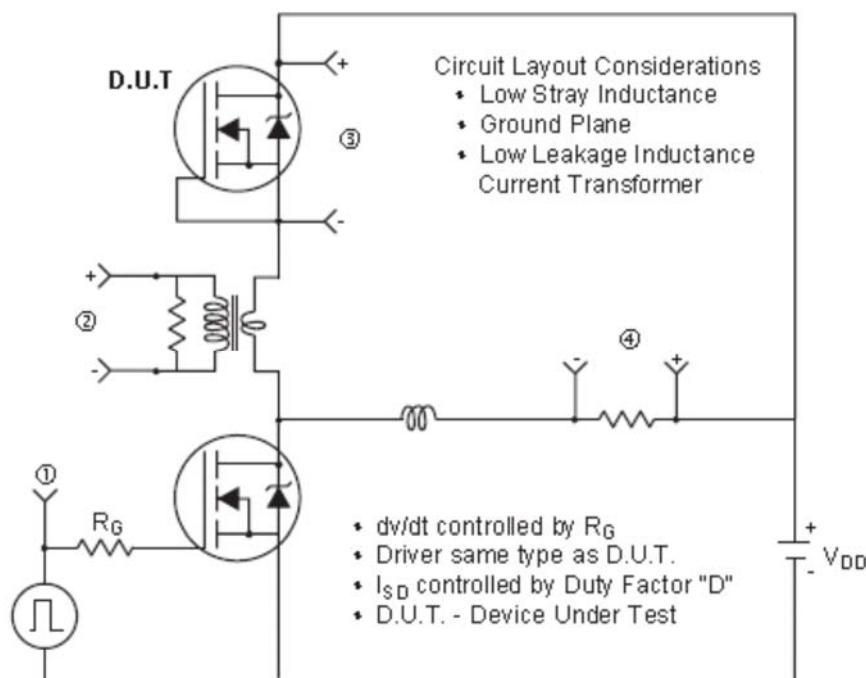


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



\*  $V_{GS} = 5V$  for Logic Level Devices

Figure 4:Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)